Agilent 4080 Series
of Parametric Testers

Are You Ready to Migrate to the Platform that Solves Your Toughest Test Challenges?
Advanced measurement challenges require new solutions

**Semiconductor manufacturing processes and new process technologies have created difficult challenges for production parametric test systems**

- Variations in device parameters at and below the 45 nanometer level are much harder to control, and require much more parametric test data to be captured than in the past.
- The use of “technology boosters,” such as high-k gate dielectrics and strained silicon, necessitate more and different types of testing than in previous generations of silicon.
- The pulse generation requirements of state-of-the art flash memory cells have exceeded the capabilities of previously available parametric testers.
- The RF testing needs of high-speed processes create both calibration and throughput restraints in production.

These factors demand new and more innovative test methodologies to keep pace with the needs of production parametric wafer testing.
The Agilent 4080 Series overcomes difficult process test challenges

Agilent solutions represent a revolutionary improvement in production parametric testing

The 4080 Series is designed to meet the measurement challenges presented by both current and cutting-edge semiconductor technologies. The 4082A combines digital architecture improvements and an ultra-fast CPU with synchronous and asynchronous parallel test capabilities. This improves the throughput of both conventional and advanced processes. The 4082F supports new high-voltage semiconductor pulse generator (HV-SPGU) modules with pulsing capabilities, which are optimized for the characterization of state-of-the-art flash memory cell technologies. The 4082A’s and 4082F’s revolutionary test capabilities provide benefits for both current and advanced production parametric test. For customers who have RF device testing needs, the 4083A offers PNA support for RF S-parameter measurement with an optional 8 x 10 RF matrix. This provides unprecedented DC and RF test capability for both development and production parametric test.

Agilent 4080 Series of Parametric Testers

In addition to meeting the testing challenges of advanced processes, the flexible 4080 Series can also boost measurement throughput for existing process technologies.
Innovative design increases speed and reduces costs

Architecture improvements boost measurement throughput

The 4080 Series employs cutting-edge architecture (including an ultra-fast CPU) that can yield speed improvements of up to 10 to 20 percent on test plans transferred from the Agilent 4070 Series of testers. This provides an immediate boost to measurement throughput without having to make any fundamental changes to the measurement methodology or to the test code being executed. You can expand the test capacity of existing wafer fabs with the 4080 Series and realize lower cost-of-test without having to change any of your SPECS or SPECS-FA test plans.
Core platform provides powerful measurement capabilities

The Agilent 4080 Series covers a wide range of parametric test needs

The 4080 Series offers a wide range of measurement capabilities required for fundamental parametric test. For example, you can easily perform DC and capacitance measurements such as Vth, Ids, Idoff, and Cox, to name just a few. The 4080 Series supports three types of SMUs for DC measurement. In addition, the 4080 Series supports an HSCMU module with 1 kHz to 2 MHz capacitance measurement capability. Several other instrument options, such as a digital volt meter (DVM), a spectrum analyzer and an external LCR meter, provide enhanced measurement capabilities. The DVM measurement resolution of 0.1 µV is helpful in evaluating low-voltage applications such as Cu metal resistance, which is critical for determining RC delays. The spectrum analyzer supports automated ring oscillator measurement in conjunction with an optional high-frequency (HF) matrix.

Advanced technology provides unmatched low-level measurement performance

All 4080 Series testers support two types of DC switching matrix cards: a standard low-current version and an ultra low-current version. Measurement resolution of 10 fA and 2 µV is achieved by using MPSMUs and the standard DC matrix card. The ultra low-current DC matrix card, which is based on Agilent’s proprietary Cool Guard relay technology, enables measurement resolution down to 1 fA (using the HRSMUs) and 0.1 µV (using the supported DVM). In addition, dielectric absorption, noise floor and settling time are all reduced, resulting in increased throughput. This ultra low-current measurement capability is essential for many leading-edge process technologies when evaluating important parameters such as inter-metal leakage and memory cell leakage currents.
Advanced asynchronous and synchronous parallel test technology . . .

Virtual multiple testhead technology dramatically improves measurement throughput

All 4080 Series testers feature powerful virtual multiple testhead technology that enables asynchronous test. This ground-breaking technology allows separate measurement tasks to run independently. Unlike conventional parallel test schemes, no measurement time is ever wasted. As soon as one set of resources finishes making a measurement it can immediately start the next measurement. The net effect is like having independent multiple testheads in a single tester, which greatly increases measurement throughput.

Agilent’s virtual multiple testhead technology eliminates measurement dead time and provides the fastest possible parallel testing throughput.
Synchronously measure up to eight devices

In addition to supporting asynchronous parallel measurement, 4080 Series testers also support ultra-fast synchronous parallel measurement. With the 4080 Series, you can use all of the installed SMUs (up to eight) to make simultaneous synchronous measurements. Synchronous parallel measurement is an extremely efficient measurement technique when measuring a small array of devices (such as a group of resistors or transistors), where each device under test (DUT) requires only a single SMU.

Parallel test capabilities lower cost-of-test

Agilent’s asynchronous and synchronous parallel test capabilities can reduce test times by 50 percent or more* over conventional serial techniques. The net result is dramatically improved throughput and lower cost-of-test.

*Percent test time is reduced depends upon the TEG design and test plan optimization.
The Agilent 4082F is a complete flash cell testing solution

Fast and efficient production test of NAND and NOR flash technologies
The 4082F has the same superb parametric test capabilities as the 4082A. It is the first production parametric test system to support a semiconductor pulse generator unit (SPGU) mainframe as well as high-voltage (HV-SPGU) modules that are fully integrated into the system hardware. The HV-SPGU offers best-in-class pulse generation capability for modern advanced flash memory testing. The powerful capabilities shown below enable you to meet almost any flash cell testing need from R&D to production.

<table>
<thead>
<tr>
<th>Features</th>
<th>Benefits</th>
</tr>
</thead>
<tbody>
<tr>
<td>Voltage output from -40 V to +40 V (80 Vpp)</td>
<td>Meets the needs of modern NAND flash memory test</td>
</tr>
<tr>
<td>Voltage resolution of 0.4 mV</td>
<td>Enables the creation of waveforms with accurate and precise pulse levels to characterize multilevel cell (MLC) structures and other advanced flash devices</td>
</tr>
<tr>
<td>Two channels per module, with up to five modules supported</td>
<td>Allows you to have up to ten independent, synchronized pulse channels for flash cell testing</td>
</tr>
<tr>
<td>Arbitrary Linear Waveform Generation (ALWG)</td>
<td>Supports creation of customized waveforms and permits characterization of next-generation flash device such as those using trapped-charge schemes</td>
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The 4082F’s HV-SPGUs can output three-level waveforms at +/- 40 V (80 V peak-to-peak), which enables the characterization of advanced NAND cell flash memory processes.

The arbitrary linear waveform generation capability of the 4082F’s HV-SPGUs makes it easy to create complex waveforms.
The Agilent 4083A provides all-in-one DC to RF test capability

**Advanced RF test capabilities improve throughput and reduce costs**

Supporting all of the measurement capabilities of the 4082A and 4082F, the 4083A is designed to meet the most difficult characterization challenges posed by RF semiconductor devices. The 4083A supports an Agilent PNA Network Analyzer for high-frequency S-parameter measurements up to 20 GHz, easily meeting the testing needs of modern RF devices. To help those unfamiliar with RF measurement, the 4083A is furnished with a library of both RF and RFCV algorithms. The 4083A is also the first production parametric tester to offer an 8 x10 RF matrix option integrated in the testhead that supports 20 GHz measurements. With the ability to measure up to five RF test structures in a single touchdown, the 4083A RF matrix both improves measurement throughput and increases probe card lifetime by reducing contact wear-and-tear.

**Production-ready capabilities**

The 4083A easily integrates into high-volume manufacturing environments. With 10 RF ports and up to 48 DC pins, the 4083A supports direct-docking style probe cards. This makes it easy for operators to change probe cards and it also supports the use of automated probe card changers. The 4083A also provides automated software to calibrate the RF measurement resources automatically (SOLT, SOL, and Open/Short de-embedding), and this software can easily be used by a technician or operator.
Code reusability enables fast production ramp-up

Compatibility with existing platforms reduces transition costs
Agilent SPECS and SPECS-FA test plans and algorithms created on 4070 Series test platforms will run without modification on the Linux-based 4080 Series. This minimizes transition costs, permits the reuse of existing code, and lowers the cost of ownership by enabling the use of lower-cost Linux workstations. It also enables existing wafer fabs to ramp up quickly and to take advantage of superior 4080 Series performance to boost throughput. This compatibility protects your measurement investment by making it easy to transition from the 4070 Series to the 4080 Series and to maintain a mixed tester environment.

Agilent SPECS-FA provides seamless SECS/GEM integration
Agilent SPECS-FA, the factory automation version of Agilent SPECS, offers all the features and capabilities of Agilent SPECS and fully supports SEMI automation standards E5 (SECS II), E30 (GEM), E87 (CMS), E39 (OSS), E40 (PMS), E90 (STS), and E94 (CJM). In addition, Agilent SPECS-FA can report the status of both the 4080 Series tester and the wafer prober in real time. This means the host controller always knows the exact status of the test cell. These capabilities have made Agilent SPECS-FA the de facto worldwide industry standard for 300 mm wafer fabs.

SPECS-FA is compatible with SEMI standards and enables the easy monitoring of each test cell in "lights-out" production environments.
Are you ready to migrate to the platform that can solve your most difficult parametric test challenges?

**Agilent 4082A**

*Next-generation parametric tester with unparalleled measurement throughput and accuracy*

- Improved tester architecture can reduce test times by 10 to 20 percent
- Synchronous and asynchronous parallel test can improve throughput by 50 percent or more*
- 1 fA and 0.1 μV measurement resolution
- Optional HSCMU
- Ring oscillator measurement solution option

**Agilent 4082F**

*Production-ready solution for state-of-the-art flash memory evaluation*

- Same measurement capabilities as the 4082A
- Integrated HV-SPGUs
  - Up to 10 channels total
  - ± 40 V output capability
- Two or three level pulsing on each channel
- ALWG capability
- Fast and reliable operation

**Agilent 4083A**

*Production RF measurements as easy as DC*

- Same measurement capabilities as the 4082A and 4082F
- Integrated PNA option for S-parameter and RFCV measurement
- Easy-to-use RF calibration routines
- Optional 20 GHz 8 x 10 RF matrix improves throughput and extends probe card life

*Percent test time is reduced depends upon the TEG design and test plan optimization.

Contact your local Agilent representative to learn more about how the 4080 Series can lower your cost-of-test.
Web Resources

4080 Series Web Site
Visit our 4080 Web site for additional product information and literature.
www.agilent.com/see/4080

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For more information about the B1500A Semiconductor Device Analyzer and EasyEXPERT software, please call one of the centers listed below and ask to speak with an Agilent sales representative.

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